

Welcome to [E-XFL.COM](https://www.e-xfl.com)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I ² C, LINbus, SPI, TSI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	40
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D - 16bit; D/A - 12bit
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-QFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkl16z64vft4r

Table of Contents

1 Ratings.....	4	3.6.2 CMP and 6-bit DAC electrical specifications.....	29
1.1 Thermal handling ratings.....	4	3.6.3 12-bit DAC electrical characteristics.....	31
1.2 Moisture handling ratings.....	4	3.7 Timers.....	34
1.3 ESD handling ratings.....	4	3.8 Communication interfaces.....	34
1.4 Voltage and current operating ratings.....	4	3.8.1 SPI switching specifications.....	34
2 General.....	5	3.8.2 Inter-Integrated Circuit Interface (I2C) timing.....	39
2.1 AC electrical characteristics.....	5	3.8.3 UART.....	40
2.2 Nonswitching electrical specifications.....	5	3.8.4 I2S/SAI switching specifications.....	40
2.2.1 Voltage and current operating requirements.....	6	3.9 Human-machine interfaces (HMI).....	44
2.2.2 LVD and POR operating requirements.....	6	3.9.1 TSI electrical specifications.....	44
2.2.3 Voltage and current operating behaviors.....	7	4 Dimensions.....	45
2.2.4 Power mode transition operating behaviors.....	8	4.1 Obtaining package dimensions.....	45
2.2.5 Power consumption operating behaviors.....	9	5 Pinout.....	45
2.2.6 EMC radiated emissions operating behaviors... ..	14	5.1 KL16 Signal Multiplexing and Pin Assignments.....	45
2.2.7 Designing with radiated emissions in mind.....	15	5.2 KL16 pinouts.....	48
2.2.8 Capacitance attributes.....	15	6 Ordering parts.....	51
2.3 Switching specifications.....	15	6.1 Determining valid orderable parts.....	51
2.3.1 Device clock specifications.....	15	7 Part identification.....	51
2.3.2 General switching specifications.....	16	7.1 Description.....	52
2.4 Thermal specifications.....	16	7.2 Format.....	52
2.4.1 Thermal operating requirements.....	16	7.3 Fields.....	52
2.4.2 Thermal attributes.....	17	7.4 Example.....	52
3 Peripheral operating requirements and behaviors.....	17	8 Terminology and guidelines.....	53
3.1 Core modules.....	17	8.1 Definition: Operating requirement.....	53
3.1.1 SWD electricals	17	8.2 Definition: Operating behavior.....	53
3.2 System modules.....	19	8.3 Definition: Attribute.....	53
3.3 Clock modules.....	19	8.4 Definition: Rating.....	54
3.3.1 MCG specifications.....	19	8.5 Result of exceeding a rating.....	54
3.3.2 Oscillator electrical specifications.....	21	8.6 Relationship between ratings and operating requirements.....	54
3.4 Memories and memory interfaces.....	23	8.7 Guidelines for ratings and operating requirements.....	55
3.4.1 Flash electrical specifications.....	23	8.8 Definition: Typical value.....	55
3.5 Security and integrity modules.....	24	8.9 Typical value conditions.....	56
3.6 Analog.....	24	9 Revision history.....	57
3.6.1 ADC electrical specifications.....	24		

1 Ratings

1.1 Thermal handling ratings

Table 1. Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T _{STG}	Storage temperature	-55	150	°C	1
T _{SDR}	Solder temperature, lead-free	—	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.
2. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

1.2 Moisture handling ratings

Table 2. Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

1.3 ESD handling ratings

Table 3. ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V _{HBM}	Electrostatic discharge voltage, human body model	-2000	+2000	V	1
V _{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I _{LAT}	Latch-up current at ambient temperature of 105 °C	-100	+100	mA	3

1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
2. Determined according to JEDEC Standard JESD22-C101, *Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components*.
3. Determined according to JEDEC Standard JESD78, *IC Latch-Up Test*.

1.4 Voltage and current operating ratings

Table 4. Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
V_{DD}	Digital supply voltage	-0.3	3.8	V
I_{DD}	Digital supply current	—	120	mA
V_{IO}	IO pin input voltage	-0.3	$V_{DD} + 0.3$	V
I_D	Instantaneous maximum current single pin limit (applies to all port pins)	-25	25	mA
V_{DDA}	Analog supply voltage	$V_{DD} - 0.3$	$V_{DD} + 0.3$	V

2 General

2.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.

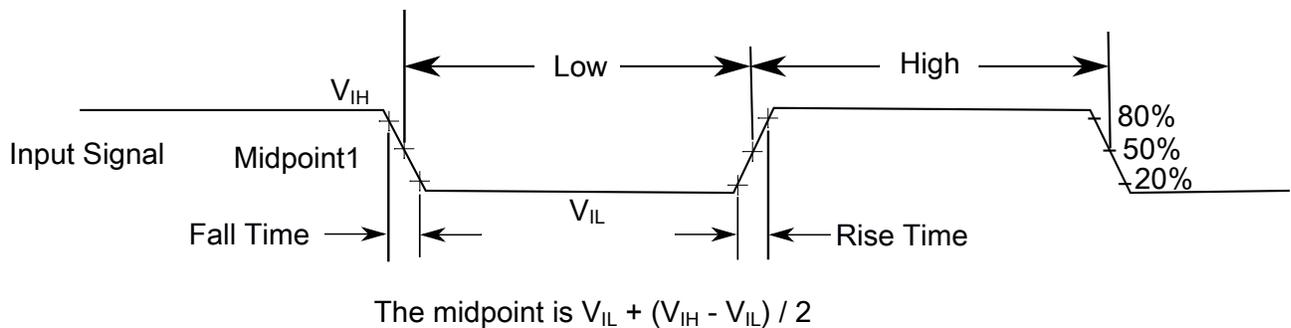


Figure 1. Input signal measurement reference

All digital I/O switching characteristics, unless otherwise specified, assume the output pins have the following characteristics.

- $C_L=30$ pF loads
- Slew rate disabled
- Normal drive strength

2.2 Nonswitching electrical specifications

Table 6. V_{DD} supply LVD and POR operating requirements (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V _{LW1H}	<ul style="list-style-type: none"> Level 1 falling (LVWV = 00) 	2.62	2.70	2.78	V	
V _{LW2H}	<ul style="list-style-type: none"> Level 2 falling (LVWV = 01) 	2.72	2.80	2.88	V	
V _{LW3H}	<ul style="list-style-type: none"> Level 3 falling (LVWV = 10) 	2.82	2.90	2.98	V	
V _{LW4H}	<ul style="list-style-type: none"> Level 4 falling (LVWV = 11) 	2.92	3.00	3.08	V	
V _{HYSH}	Low-voltage inhibit reset/recover hysteresis — high range	—	±60	—	mV	—
V _{LVDL}	Falling low-voltage detect threshold — low range (LVDV=00)	1.54	1.60	1.66	V	—
V _{LW1L}	Low-voltage warning thresholds — low range <ul style="list-style-type: none"> Level 1 falling (LVWV = 00) 	1.74	1.80	1.86	V	1
V _{LW2L}	<ul style="list-style-type: none"> Level 2 falling (LVWV = 01) 	1.84	1.90	1.96	V	
V _{LW3L}	<ul style="list-style-type: none"> Level 3 falling (LVWV = 10) 	1.94	2.00	2.06	V	
V _{LW4L}	<ul style="list-style-type: none"> Level 4 falling (LVWV = 11) 	2.04	2.10	2.16	V	
V _{HYSL}	Low-voltage inhibit reset/recover hysteresis — low range	—	±40	—	mV	—
V _{BG}	Bandgap voltage reference	0.97	1.00	1.03	V	—
t _{LPO}	Internal low power oscillator period — factory trimmed	900	1000	1100	µs	—

1. Rising thresholds are falling threshold + hysteresis voltage

2.2.3 Voltage and current operating behaviors

Table 7. Voltage and current operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V _{OH}	Output high voltage — Normal drive pad (except RESET_b) <ul style="list-style-type: none"> 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OH} = -5 mA 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OH} = -2.5 mA 	V _{DD} - 0.5 V _{DD} - 0.5	— —	V V	1, 2
V _{OH}	Output high voltage — High drive pad (except RESET_b) <ul style="list-style-type: none"> 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OH} = -20 mA 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OH} = -10 mA 	V _{DD} - 0.5 V _{DD} - 0.5	— —	V V	1, 2
I _{OHT}	Output high current total for all ports	—	100	mA	
V _{OL}	Output low voltage — Normal drive pad <ul style="list-style-type: none"> 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OL} = 5 mA 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OL} = 2.5 mA 	— —	0.5 0.5	V V	1

Table continues on the next page...

Table 7. Voltage and current operating behaviors (continued)

Symbol	Description	Min.	Max.	Unit	Notes
V _{OL}	Output low voltage — High drive pad <ul style="list-style-type: none"> • 2.7 V ≤ V_{DD} ≤ 3.6 V, I_{OL} = 20 mA • 1.71 V ≤ V_{DD} ≤ 2.7 V, I_{OL} = 10 mA 	—	0.5	V	1
		—	0.5	V	
I _{OLT}	Output low current total for all ports	—	100	mA	
I _{IN}	Input leakage current (per pin) for full temperature range	—	1	μA	3
I _{IN}	Input leakage current (per pin) at 25 °C	—	0.025	μA	3
I _{IN}	Input leakage current (total all pins) for full temperature range	—	65	μA	3
I _{OZ}	Hi-Z (off-state) leakage current (per pin)	—	1	μA	
R _{PU}	Internal pullup resistors	20	50	kΩ	4

1. PTB0, PTB1, PTD6, and PTD7 I/O have both high drive and normal drive capability selected by the associated PTx_PCRn[DSE] control bit. All other GPIOs are normal drive only.
2. The reset pin only contains an active pull down device when configured as the RESET signal or as a GPIO. When configured as a GPIO output, it acts as a pseudo open drain output.
3. Measured at V_{DD} = 3.6 V
4. Measured at V_{DD} supply voltage = V_{DD} min and V_{input} = V_{SS}

2.2.4 Power mode transition operating behaviors

All specifications except t_{POR} and VLLS_x→RUN recovery times in the following table assume this clock configuration:

- CPU and system clocks = 48 MHz
- Bus and flash clock = 24 MHz
- FEI clock mode

POR and VLLS_x→RUN recovery use FEI clock mode at the default CPU and system frequency of 21 MHz, and a bus and flash clock frequency of 10.5 MHz.

Table 8. Power mode transition operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t _{POR}	After a POR event, amount of time from the point V _{DD} reaches 1.8 V to execution of the first instruction across the operating temperature range of the chip.	—	—	300	μs	1
	<ul style="list-style-type: none"> • VLLS0 → RUN 	—	106	120	μs	

Table continues on the next page...

Table 8. Power mode transition operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	• VLLS1 → RUN	—	105	117	μs	
	• VLLS3 → RUN	—	47	54	μs	
	• LLS → RUN	—	4.5	5.0	μs	
	• VLPS → RUN	—	4.5	5.0	μs	
	• STOP → RUN	—	4.5	5.0	μs	

1. Normal boot (FTFA_FOPT[LPBOOT]=11).

2.2.5 Power consumption operating behaviors

The maximum values stated in the following table represent characterized results equivalent to the mean plus three times the standard deviation (mean + 3 sigma).

Table 9. Power consumption operating behaviors

Symbol	Description	Temp.	Typ.	Max	Unit	Note
I _{DDA}	Analog supply current	—	—	See note	mA	1
I _{DD_RUNCO_CM}	Run mode current in compute operation - 48 MHz core / 24 MHz flash/ bus disabled, LPTMR running using 4 MHz internal reference clock, CoreMark® benchmark code executing from flash, at 3.0 V	—	6.1	—	mA	2
I _{DD_RUNCO}	Run mode current in compute operation - 48 MHz core / 24 MHz flash / bus clock disabled, code of while(1) loop executing from flash, at 3.0 V	—	3.8	4.4	mA	3
I _{DD_RUN}	Run mode current - 48 MHz core / 24 MHz bus and flash, all peripheral clocks disabled, code executing from flash, at 3.0 V	—	4.6	5.2	mA	3
I _{DD_RUN}	Run mode current - 48 MHz core / 24 MHz bus and flash, all peripheral clocks enabled, code executing from flash, at 3.0 V	at 25 °C	6.0	6.2	mA	3, 4
		at 70 °C	6.2	6.4	mA	
		at 125 °C	6.2	6.5	mA	

Table continues on the next page...

Table 10. Low power mode peripheral adders — typical value

Symbol	Description	Temperature (°C)						Unit
		-40	25	50	70	85	105	
	placing the device in STOP or VLPS mode. ADC is configured for low power mode using the internal clock and continuous conversions.							

2.2.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG in FBE for run mode, and BLPE for VLPR mode
- No GPIOs toggled
- Code execution from flash with cache enabled
- For the ALLOFF curve, all peripheral clocks are disabled except FTFA

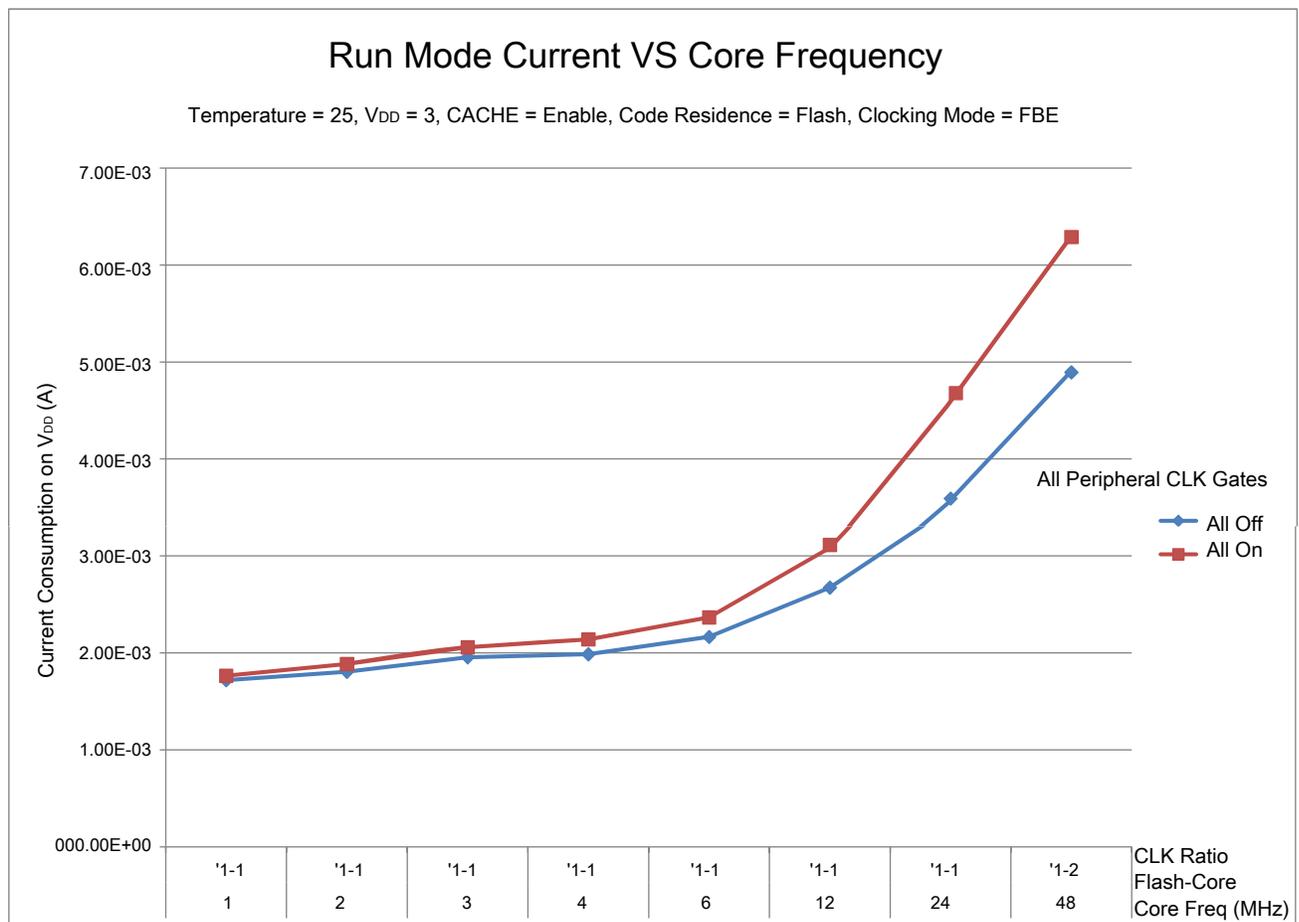


Figure 2. Run mode supply current vs. core frequency

Table 13. Device clock specifications (continued)

Symbol	Description	Min.	Max.	Unit
f _{LPTMR_ERCLK}	LPTMR external reference clock	—	16	MHz
f _{osc_hi_2}	Oscillator crystal or resonator frequency — high frequency mode (high range) (MCG_C2[RANGE]=1x)	—	16	MHz
f _{TPM}	TPM asynchronous clock	—	8	MHz
f _{UART0}	UART0 asynchronous clock	—	8	MHz

1. The frequency limitations in VLPR and VLPS modes here override any frequency specification listed in the timing specification for any other module. These same frequency limits apply to VLPS, whether VLPS was entered from RUN or from VLPR.
2. The LPTMR can be clocked at this speed in VLPR or VLPS only when the source is an external pin.

2.3.2 General switching specifications

These general-purpose specifications apply to all signals configured for GPIO and UART signals.

Table 14. General switching specifications

Description	Min.	Max.	Unit	Notes
GPIO pin interrupt pulse width (digital glitch filter disabled) — Synchronous path	1.5	—	Bus clock cycles	1
External RESET and NMI pin interrupt pulse width — Asynchronous path	100	—	ns	2
GPIO pin interrupt pulse width — Asynchronous path	16	—	ns	2
Port rise and fall time	—	36	ns	3

1. The greater synchronous and asynchronous timing must be met.
2. This is the shortest pulse that is guaranteed to be recognized.
3. 75 pF load

2.4 Thermal specifications

2.4.1 Thermal operating requirements

Table 15. Thermal operating requirements

Symbol	Description	Min.	Max.	Unit
T _J	Die junction temperature	−40	125	°C
T _A	Ambient temperature	−40	105	°C

Table 19. Oscillator DC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
		—	0	—	kΩ	
V_{pp}^5	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — low-frequency, high-gain mode (HGO=1)	—	V_{DD}	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, low-power mode (HGO=0)	—	0.6	—	V	
	Peak-to-peak amplitude of oscillation (oscillator mode) — high-frequency, high-gain mode (HGO=1)	—	V_{DD}	—	V	

1. $V_{DD}=3.3$ V, Temperature =25 °C
2. See crystal or resonator manufacturer's recommendation
3. C_x, C_y can be provided by using the integrated capacitors when the low frequency oscillator (RANGE = 00) is used. For all other cases external capacitors must be used.
4. When low power mode is selected, R_F is integrated and must not be attached externally.
5. The EXTAL and XTAL pins should only be connected to required oscillator components and must not be connected to any other devices.

3.3.2.2 Oscillator frequency specifications

Table 20. Oscillator frequency specifications

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
f_{osc_lo}	Oscillator crystal or resonator frequency — low-frequency mode (MCG_C2[RANGE]=00)	32	—	40	kHz	
$f_{osc_hi_1}$	Oscillator crystal or resonator frequency — high-frequency mode (low range) (MCG_C2[RANGE]=01)	3	—	8	MHz	
$f_{osc_hi_2}$	Oscillator crystal or resonator frequency — high frequency mode (high range) (MCG_C2[RANGE]=1x)	8	—	32	MHz	
f_{ec_extal}	Input clock frequency (external clock mode)	—	—	48	MHz	1, 2
t_{dc_extal}	Input clock duty cycle (external clock mode)	40	50	60	%	
t_{cst}	Crystal startup time — 32 kHz low-frequency, low-power mode (HGO=0)	—	750	—	ms	3, 4
	Crystal startup time — 32 kHz low-frequency, high-gain mode (HGO=1)	—	250	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), low-power mode (HGO=0)	—	0.6	—	ms	
	Crystal startup time — 8 MHz high-frequency (MCG_C2[RANGE]=01), high-gain mode (HGO=1)	—	1	—	ms	

Table 26. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
	Temp sensor slope	Across the full temperature range of the device	1.55	1.62	1.69	mV/°C	8
V_{TEMP25}	Temp sensor voltage	25 °C	706	716	726	mV	8

1. All accuracy numbers assume the ADC is calibrated with $V_{REFH} = V_{DDA}$
2. Typical values assume $V_{DDA} = 3.0$ V, Temp = 25 °C, $f_{ADCK} = 2.0$ MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
3. The ADC supply current depends on the ADC conversion clock speed, conversion rate and ADC_CFG1[ADLPC] (low power). For lowest power operation, ADC_CFG1[ADLPC] must be set, the ADC_CFG2[ADHSC] bit must be clear with 1 MHz ADC conversion clock speed.
4. $1 \text{ LSB} = (V_{REFH} - V_{REFL})/2^N$
5. ADC conversion clock < 16 MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
6. Input data is 100 Hz sine wave. ADC conversion clock < 12 MHz.
7. Input data is 1 kHz sine wave. ADC conversion clock < 12 MHz.
8. ADC conversion clock < 3 MHz

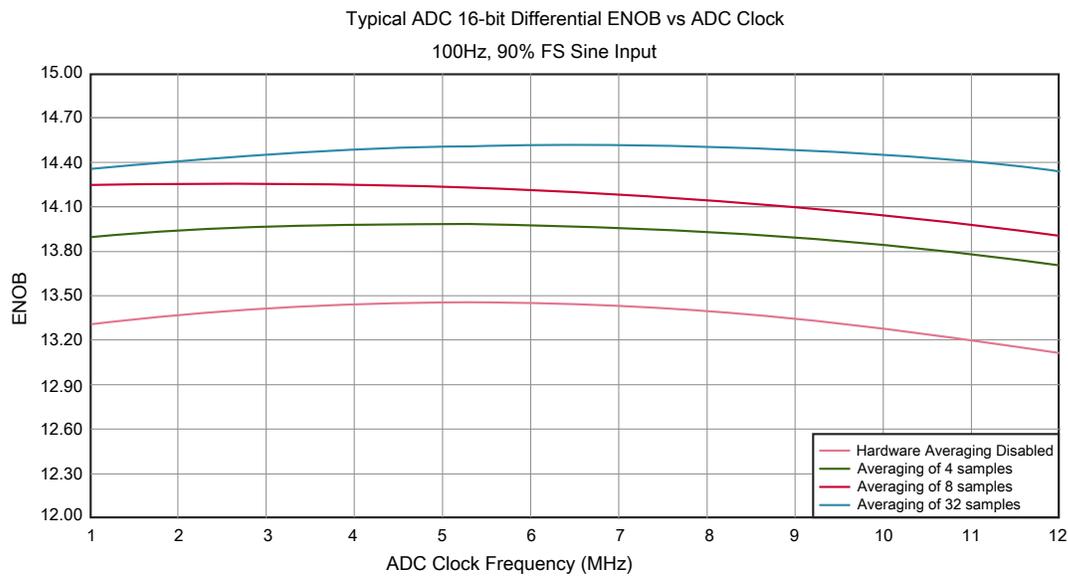


Figure 7. Typical ENOB vs. ADC_CLK for 16-bit differential mode

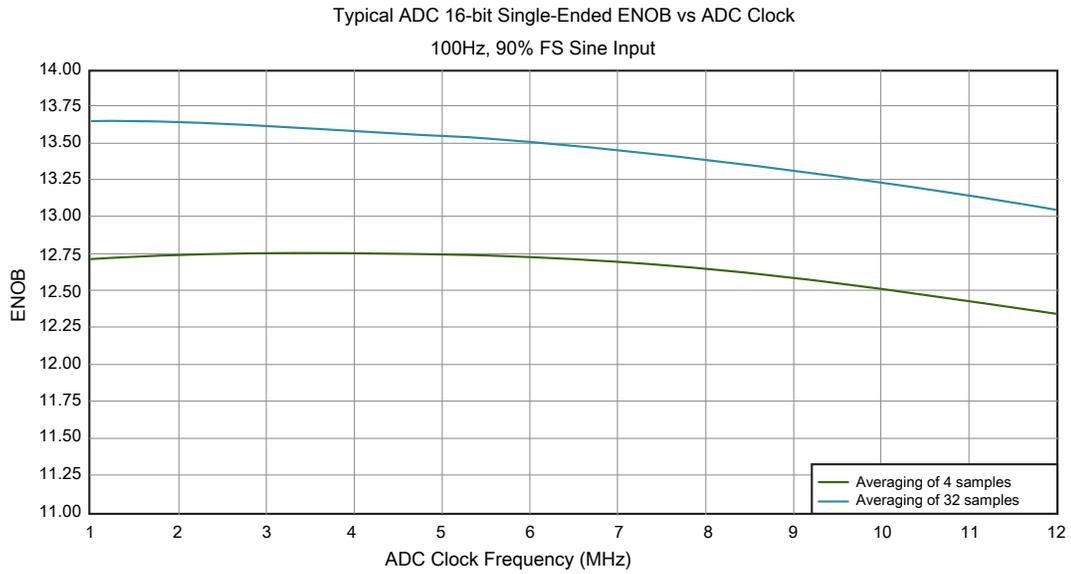


Figure 8. Typical ENOB vs. ADC_CLK for 16-bit single-ended mode

3.6.2 CMP and 6-bit DAC electrical specifications

Table 27. Comparator and 6-bit DAC electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DD}	Supply voltage	1.71	—	3.6	V
I_{DDHS}	Supply current, High-speed mode (EN=1, PMODE=1)	—	—	200	μ A
$I_{DDL S}$	Supply current, low-speed mode (EN=1, PMODE=0)	—	—	20	μ A
V_{AIN}	Analog input voltage	$V_{SS} - 0.3$	—	V_{DD}	V
V_{AIO}	Analog input offset voltage	—	—	20	mV
V_H	Analog comparator hysteresis ¹ <ul style="list-style-type: none"> • CR0[HYSTCTR] = 00 • CR0[HYSTCTR] = 01 • CR0[HYSTCTR] = 10 • CR0[HYSTCTR] = 11 	—	5 10 20 30	—	mV mV mV mV
V_{CMPOh}	Output high	$V_{DD} - 0.5$	—	—	V
V_{CMPOl}	Output low	—	—	0.5	V
t_{DHS}	Propagation delay, high-speed mode (EN=1, PMODE=1)	20	50	200	ns
t_{DLS}	Propagation delay, low-speed mode (EN=1, PMODE=0)	80	250	600	ns
	Analog comparator initialization delay ²	—	—	40	μ s

Table continues on the next page...

3.8.1 SPI switching specifications

The Serial Peripheral Interface (SPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The following tables provide timing characteristics for classic SPI timing modes. See the SPI chapter of the chip's Reference Manual for information about the modified transfer formats used for communicating with slower peripheral devices.

All timing is shown with respect to 20% V_{DD} and 80% V_{DD} thresholds, unless noted, as well as input signal transitions of 3 ns and a 30 pF maximum load on all SPI pins.

Table 30. SPI master mode timing on slew rate disabled pads

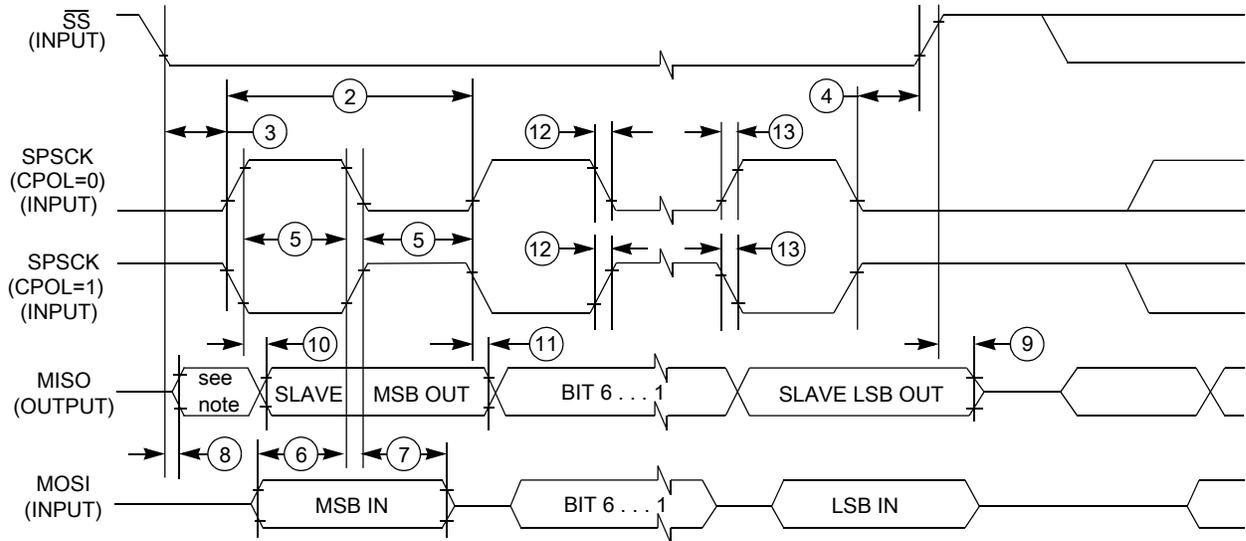
Num.	Symbol	Description	Min.	Max.	Unit	Note
1	f_{op}	Frequency of operation	$f_{periph}/2048$	$f_{periph}/2$	Hz	1
2	t_{SPSCK}	SPSCK period	$2 \times t_{periph}$	$2048 \times t_{periph}$	ns	2
3	t_{Lead}	Enable lead time	1/2	—	t_{SPSCK}	—
4	t_{Lag}	Enable lag time	1/2	—	t_{SPSCK}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	$t_{periph} - 30$	$1024 \times t_{periph}$	ns	—
6	t_{SU}	Data setup time (inputs)	18	—	ns	—
7	t_{HI}	Data hold time (inputs)	0	—	ns	—
8	t_v	Data valid (after SPSCK edge)	—	15	ns	—
9	t_{HO}	Data hold time (outputs)	0	—	ns	—
10	t_{RI}	Rise time input	—	$t_{periph} - 25$	ns	—
	t_{FI}	Fall time input				
11	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output				

1. For SPI0 f_{periph} is the bus clock (f_{BUS}). For SPI1 f_{periph} is the system clock (f_{SYS}).
2. $t_{periph} = 1/f_{periph}$

Table 31. SPI master mode timing on slew rate enabled pads

Num.	Symbol	Description	Min.	Max.	Unit	Note
1	f_{op}	Frequency of operation	$f_{periph}/2048$	$f_{periph}/2$	Hz	1
2	t_{SPSCK}	SPSCK period	$2 \times t_{periph}$	$2048 \times t_{periph}$	ns	2
3	t_{Lead}	Enable lead time	1/2	—	t_{SPSCK}	—
4	t_{Lag}	Enable lag time	1/2	—	t_{SPSCK}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	$t_{periph} - 30$	$1024 \times t_{periph}$	ns	—
6	t_{SU}	Data setup time (inputs)	96	—	ns	—
7	t_{HI}	Data hold time (inputs)	0	—	ns	—

Table continues on the next page...



NOTE: Not defined

Figure 16. SPI slave mode timing (CPHA = 1)

3.8.2 Inter-Integrated Circuit Interface (I2C) timing

Table 34. I2C timing

Characteristic	Symbol	Standard Mode		Fast Mode		Unit
		Minimum	Maximum	Minimum	Maximum	
SCL Clock Frequency	f_{SCL}	0	100	0	400 ¹	kHz
Hold time (repeated) START condition. After this period, the first clock pulse is generated.	$t_{HD}; STA$	4	—	0.6	—	μs
LOW period of the SCL clock	t_{LOW}	4.7	—	1.3	—	μs
HIGH period of the SCL clock	t_{HIGH}	4	—	0.6	—	μs
Set-up time for a repeated START condition	$t_{SU}; STA$	4.7	—	0.6	—	μs
Data hold time for I ² C bus devices	$t_{HD}; DAT$	0 ²	3.45 ³	0 ⁴	0.9 ²	μs
Data set-up time	$t_{SU}; DAT$	250 ⁵	—	100 ^{3, 6}	—	ns
Rise time of SDA and SCL signals	t_r	—	1000	$20 + 0.1C_b$ ⁷	300	ns
Fall time of SDA and SCL signals	t_f	—	300	$20 + 0.1C_b$ ⁶	300	ns
Set-up time for STOP condition	$t_{SU}; STO$	4	—	0.6	—	μs
Bus free time between STOP and START condition	t_{BUF}	4.7	—	1.3	—	μs
Pulse width of spikes that must be suppressed by the input filter	t_{SP}	N/A	N/A	0	50	ns

1. The maximum SCL Clock Frequency in Fast mode with maximum bus loading can only be achieved when using the High drive pins (see [Voltage and current operating behaviors](#)) or when using the Normal drive pins and $VDD \geq 2.7 V$

Peripheral operating requirements and behaviors

2. The master mode I²C deasserts ACK of an address byte simultaneously with the falling edge of SCL. If no slaves acknowledge this address byte, then a negative hold time can result, depending on the edge rates of the SDA and SCL lines.
3. The maximum t_{HD; DAT} must be met only if the device does not stretch the LOW period (t_{LOW}) of the SCL signal.
4. Input signal Slew = 10 ns and Output Load = 50 pF
5. Set-up time in slave-transmitter mode is 1 IPBus clock period, if the TX FIFO is empty.
6. A Fast mode I²C bus device can be used in a Standard mode I²C bus system, but the requirement t_{SU; DAT} ≥ 250 ns must then be met. This is automatically the case if the device does not stretch the LOW period of the SCL signal. If such a device does stretch the LOW period of the SCL signal, then it must output the next data bit to the SDA line t_{rmax} + t_{SU; DAT} = 1000 + 250 = 1250 ns (according to the Standard mode I²C bus specification) before the SCL line is released.
7. C_b = total capacitance of the one bus line in pF.

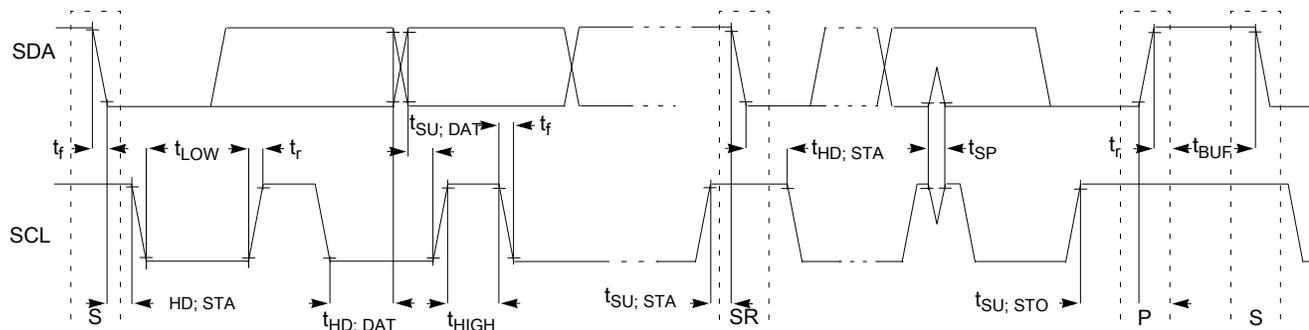


Figure 17. Timing definition for fast and standard mode devices on the I²C bus

3.8.3 UART

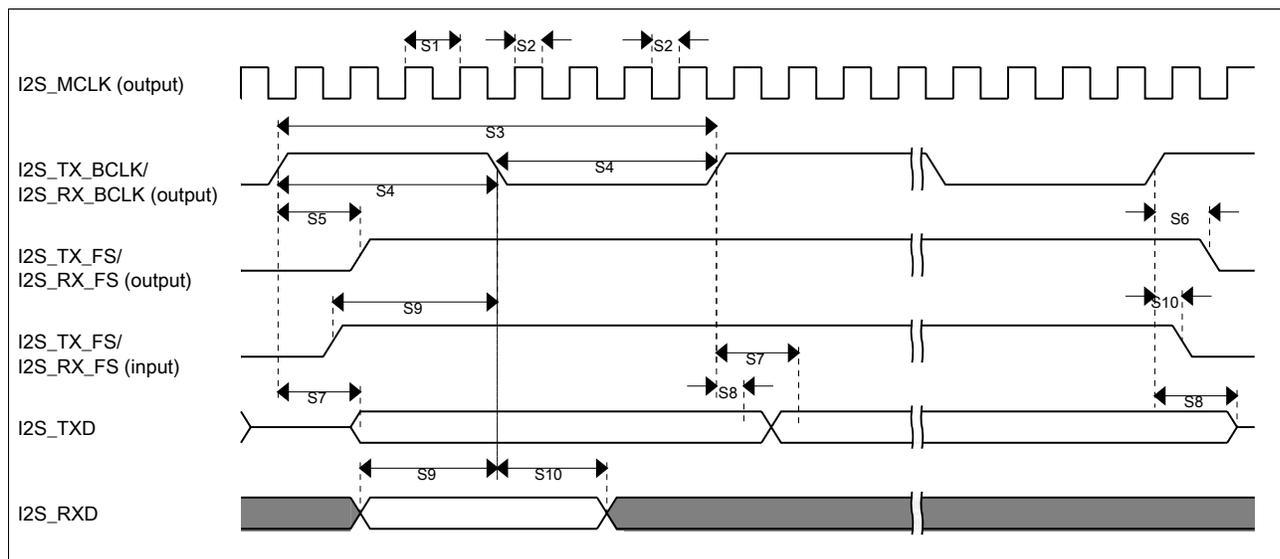
See [General switching specifications](#).

3.8.4 I2S/SAI switching specifications

This section provides the AC timing for the I2S/SAI module in master mode (clocks are driven) and slave mode (clocks are input). All timing is given for noninverted serial clock polarity (TCR2[BCP] is 0, RCR2[BCP] is 0) and a noninverted frame sync (TCR4[FSP] is 0, RCR4[FSP] is 0). If the polarity of the clock and/or the frame sync have been inverted, all the timing remains valid by inverting the bit clock signal (BCLK) and/or the frame sync (FS) signal shown in the following figures.

Table 37. I2S/SAI master mode timing in VLPR, VLPW, and VLPS modes (full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	62.5	—	ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	250	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	—	45	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid		—	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	45	ns
S8	I2S_TX_BCLK to I2S_TXD invalid		—	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK		—	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	—	ns


Figure 20. I2S/SAI timing — master modes
Table 38. I2S/SAI slave mode timing in VLPR, VLPW, and VLPS modes (full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	250	—	ns

Table continues on the next page...

64 LQFP	48 QFN	32 QFN	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7
31	23	16	VSS	VSS	VSS							
32	24	17	PTA18	EXTAL0	EXTAL0	PTA18		UART1_RX	TPM_CLKIN0			
33	25	18	PTA19	XTAL0	XTAL0	PTA19		UART1_TX	TPM_CLKIN1		LPTMR0_ALT1	
34	26	19	PTA20	RESET_b		PTA20						RESET_b
35	27	20	PTB0/ LLWU_P5	ADC0_SE8/ TSIO_CH0	ADC0_SE8/ TSIO_CH0	PTB0/ LLWU_P5	I2C0_SCL	TPM1_CH0				
36	28	21	PTB1	ADC0_SE9/ TSIO_CH6	ADC0_SE9/ TSIO_CH6	PTB1	I2C0_SDA	TPM1_CH1				
37	29	—	PTB2	ADC0_SE12/ TSIO_CH7	ADC0_SE12/ TSIO_CH7	PTB2	I2C0_SCL	TPM2_CH0				
38	30	—	PTB3	ADC0_SE13/ TSIO_CH8	ADC0_SE13/ TSIO_CH8	PTB3	I2C0_SDA	TPM2_CH1				
39	31	—	PTB16	TSIO_CH9	TSIO_CH9	PTB16	SPI1_MOSI	UART0_RX	TPM_CLKIN0	SPI1_MISO		
40	32	—	PTB17	TSIO_CH10	TSIO_CH10	PTB17	SPI1_MISO	UART0_TX	TPM_CLKIN1	SPI1_MOSI		
41	—	—	PTB18	TSIO_CH11	TSIO_CH11	PTB18		TPM2_CH0	I2S0_TX_BCLK			
42	—	—	PTB19	TSIO_CH12	TSIO_CH12	PTB19		TPM2_CH1	I2S0_TX_FS			
43	33	—	PTC0	ADC0_SE14/ TSIO_CH13	ADC0_SE14/ TSIO_CH13	PTC0		EXTRG_IN		CMP0_OUT	I2S0_TXD0	
44	34	22	PTC1/ LLWU_P6/ RTC_CLKIN	ADC0_SE15/ TSIO_CH14	ADC0_SE15/ TSIO_CH14	PTC1/ LLWU_P6/ RTC_CLKIN	I2C1_SCL		TPM0_CH0		I2S0_TXD0	
45	35	23	PTC2	ADC0_SE11/ TSIO_CH15	ADC0_SE11/ TSIO_CH15	PTC2	I2C1_SDA		TPM0_CH1		I2S0_TX_FS	
46	36	24	PTC3/ LLWU_P7	DISABLED		PTC3/ LLWU_P7		UART1_RX	TPM0_CH2	CLKOUT	I2S0_TX_BCLK	
47	—	—	VSS	VSS	VSS							
48	—	—	VDD	VDD	VDD							
49	37	25	PTC4/ LLWU_P8	DISABLED		PTC4/ LLWU_P8	SPI0_PCS0	UART1_TX	TPM0_CH3	I2S0_MCLK		
50	38	26	PTC5/ LLWU_P9	DISABLED		PTC5/ LLWU_P9	SPI0_SCK	LPTMR0_ALT2	I2S0_RXD0		CMP0_OUT	
51	39	27	PTC6/ LLWU_P10	CMP0_IN0	CMP0_IN0	PTC6/ LLWU_P10	SPI0_MOSI	EXTRG_IN	I2S0_RX_BCLK	SPI0_MISO	I2S0_MCLK	
52	40	28	PTC7	CMP0_IN1	CMP0_IN1	PTC7	SPI0_MISO		I2S0_RX_FS	SPI0_MOSI		
53	—	—	PTC8	CMP0_IN2	CMP0_IN2	PTC8	I2C0_SCL	TPM0_CH4	I2S0_MCLK			
54	—	—	PTC9	CMP0_IN3	CMP0_IN3	PTC9	I2C0_SDA	TPM0_CH5	I2S0_RX_BCLK			
55	—	—	PTC10	DISABLED		PTC10	I2C1_SCL		I2S0_RX_FS			
56	—	—	PTC11	DISABLED		PTC11	I2C1_SDA		I2S0_RXD0			
57	41	—	PTD0	DISABLED		PTD0	SPI0_PCS0		TPM0_CH0			
58	42	—	PTD1	ADC0_SE5b	ADC0_SE5b	PTD1	SPI0_SCK		TPM0_CH1			
59	43	—	PTD2	DISABLED		PTD2	SPI0_MOSI	UART2_RX	TPM0_CH2	SPI0_MISO		

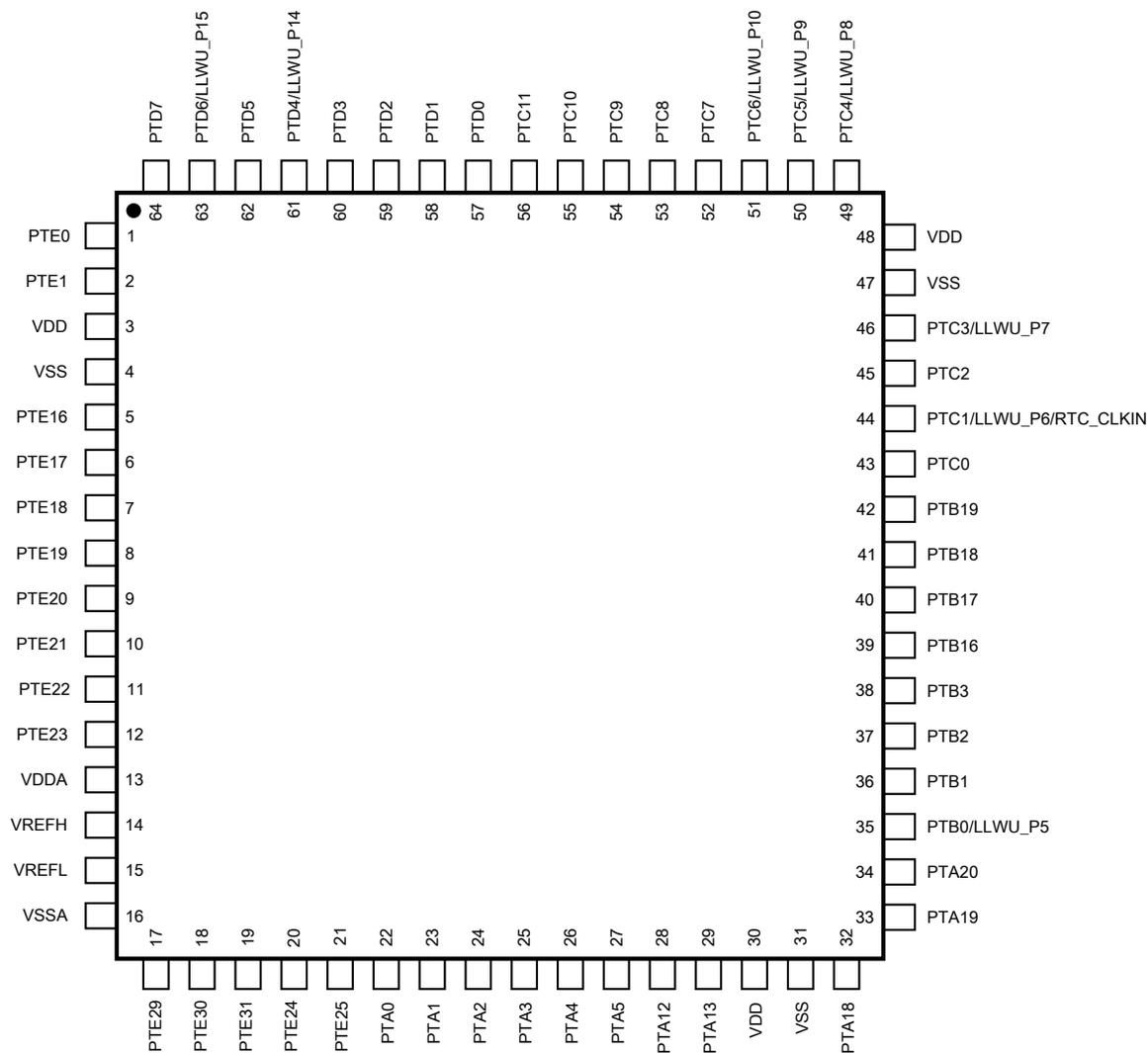


Figure 22. KL16 64-pin LQFP pinout diagram

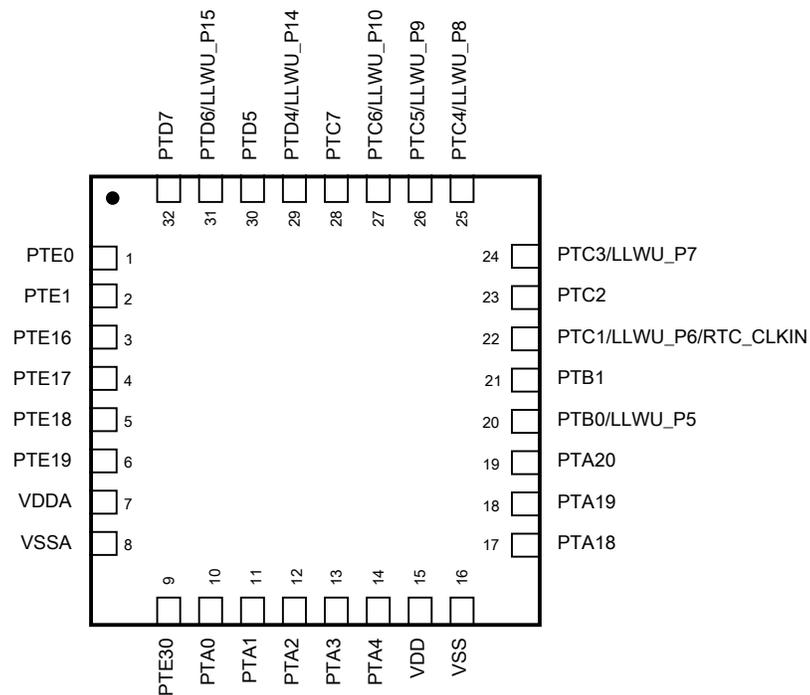


Figure 24. KL16 32-pin QFN pinout diagram

6 Ordering parts

6.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to freescale.com and perform a part number search for the following device numbers: PKL16 and MKL16

7 Part identification

7.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

7.2 Format

Part numbers for this device have the following format:

Q KL## A FFF R T PP CC N

7.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	<ul style="list-style-type: none"> M = Fully qualified, general market flow P = Prequalification
KL##	Kinetis family	<ul style="list-style-type: none"> KL16
A	Key attribute	<ul style="list-style-type: none"> Z = Cortex-M0+
FFF	Program flash memory size	<ul style="list-style-type: none"> 32 = 32 KB 64 = 64 KB 128 = 128 KB
R	Silicon revision	<ul style="list-style-type: none"> (Blank) = Main A = Revision after main
T	Temperature range (°C)	<ul style="list-style-type: none"> V = -40 to 105
PP	Package identifier	<ul style="list-style-type: none"> FM = 32 QFN (5 mm x 5 mm) FT = 48 QFN (7 mm x 7 mm) LH = 64 LQFP (10 mm x 10 mm)
CC	Maximum CPU frequency (MHz)	<ul style="list-style-type: none"> 4 = 48 MHz
N	Packaging type	<ul style="list-style-type: none"> R = Tape and reel

7.4 Example

This is an example part number:

MKL16Z128VFM4

How to Reach Us:

Home Page:

freescale.com

Web Support:

freescale.com/support

Information in this document is provided solely to enable system and software implementers to use Freescale products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits based on the information in this document. Freescale reserves the right to make changes without further notice to any products herein.

Freescale makes no warranty, representation, or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters that may be provided in Freescale data sheets and/or specifications can and do vary in different applications, and actual performance may vary over time. All operating parameters, including "typicals," must be validated for each customer application by customer's technical experts. Freescale does not convey any license under its patent rights nor the rights of others. Freescale sells products pursuant to standard terms and conditions of sale, which can be found at the following address: freescale.com/SalesTermsandConditions.

Freescale, Freescale logo, Energy Efficient Solutions logo, and Kinetis are trademarks of Freescale Semiconductor, Inc., Reg. U.S. Pat. & Tm. Off. All other product or service names are the property of their respective owners. ARM and Cortex are registered trademarks of ARM Limited (or its subsidiaries) in the EU and/or elsewhere. All rights reserved.

© 2012-2014 Freescale Semiconductor, Inc.